



Group Art Unit: 2884  
Examiner: Lee, S.

Atty. Ref.: H 2182

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants : Martin Klein et al.

Appl. No. : 10/047,556

Filed : October 23, 2001

For : DETECTOR

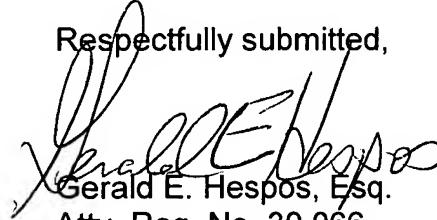
MS Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**SECOND INFORMATION DISCLOSURE STATEMENT**

Sir:

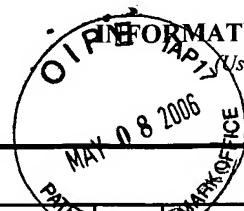
This Second Information Disclosure Statement includes a copy of Form PTO-1449 that identifies one non-patent publication. A copy of the publication is attached as well. This publication is not believed to be particularly relevant to the claimed invention. However, the discussions in this reference may be relevant to the interpretation of the Sauli reference and the comments regarding Sauli that have been made by the Examiner and the applicants herein. The Examiner is requested to consider this reference during the examination and to make the reference of record.

Respectfully submitted,



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Docket Number (Optional) H 2182	Application Number 10/047,556
Applicant(s) Martin Klein et al.	
Filing Date October 23, 2001	Group Art Unit 2884

### U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

### U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

### FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

### OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

Advances in Gas Avalanche Photomultipliers - A. Breskin et al., Dept. of Particle Physics, The Weizmann Institute of Science 76100, Rehovot, Israel - Presented at Beaune99, The Second International Conference on New Developments in Photodetection, Beaune, France, June 21-25, 1999.

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.